

BACK-END

IGBT

MOS-FET

QG TESTER QG測定装置

QGI660Z 600V

NEW

- QGI660Z has been designed to measure gate capacitance of MOS-FET and IGBT. Oscilloscope is mounted inside of tester, and it is linked with software to show measurement waveform on the software display for better efficient data management.
- MOS-FET、IGBTのゲート容量を測定するテスターです。内部にオシロスコープが組み込まれ、ソフトと連動し測定波形がソフト画面上に表示できるため、データ収集の効率化に役立ちます。

MODEL	QGI660Z	
MEASURABLE DEVICES	MOS-FET, IGBT	
MEASUREMENT RANGE		
Qgs	000.00nC~199.99nC	
Qgd	000.00nC~199.99nC	
Qg	000.00nC~499.99nC	
SETTING RANGE		
VDD	10V~600V	1V STEP
RL	0.01Ω~999.99Ω	0.01Ω STEP
IG	0.1mA~2000.0mA	0.1mA STEP
Drive-VG	0.001V~9.999V	0.001V STEP
VG-Clamp	1V~20V	1V STEP
VdHth	00.0V~20.0V	1V STEP
ΔVgth	0.1V~5.0V	0.1V STEP
QVG(VGH)	0.1V~10.0V	0.1V STEP
BINNING		
BIN INDICATION	PASS, Qg-LIMIT, ERROR, OPEN, SHORT	
DIMENSIONS & WEIGHT		
MAIN UNIT	550(W)×860(D)×1700(H)…200kg	



Measurement Waveform

